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A 1.12-ps Resolution Flash ADC-Assisted Coarse-to-Fine Time-to-Digital Converter with ADC Reference Voltage Calibration and Digital Linearity Correction

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Introduction

Wide measurement range

ADC-assisted architecture

High linearity

Linearity Improvement Technique



Digital Digital Code (N-bit) Code (N-bit) ∆t_{res} ☺ 👔 Linearity 🙂 Linearity 😕 $\mathbf{\Phi}_{error}$ Φerror Input conversion Input conversion range range



Figure 3. (a) ADC input voltage variation caused by non-uniform phase spacing, (b) ADC reference voltage calibration, (c) TDC linearity correction







Figure 1. Block diagram of the proposed TDC

- The proposed TDC employs:
- Ring-oscillator-based coarse-to-fine TDC
- Coarse conversion: multi-phase encoding





Figure 4. Simulated DNL and INL of the proposed TDC

- Achieves 1.12-ps resolution using an ADC-assisted coarse-to-fine architecture
- Supports 63-ns input dynamic range with an 8-bit counter in a ring-oscillator-based TDC
- Enables 5.6-ns conversion time by employing a flash ADC for fine conversion
- Linearity improvement by applying:
- 1. ADC reference voltage calibration (DNL 10 LSB -> 3.8 LSB)
- 2. Digital linearity correction (DNL 3.8 LSB -> 1.6 LSB)



Figure 2. TDC conversion process: (a) coarse conversion, (b) fine conversion

Figure 6. Layout view

 Table 1. Performance comparison

